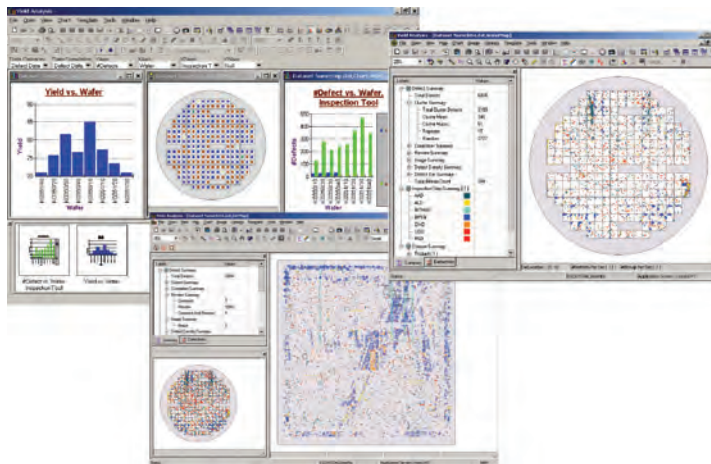


YieldManager®

- Enables chipmakers to collect, format and analyze all types of data—including defect, binsort, parametric, bitmap, WIP/MES, process and images.
- Facilitates the correlation of all types of fab data, making it faster and easier to differentiate between symptoms and probable root causes of yield problems.
- Improves productivity through automated analysis—captures analytical processes using VB Script recording, editing and execution features.
- Ensures data security with a 3-tier system approach that gives administrators powerful and versatile tools for controlled data flow.
- Reduces infrastructure costs by facilitating consolidation of multiple data systems into a single, reliable database, thus drastically reducing IT complexity and related costs.

YieldManager is a customizable yield-management software system that helps IC manufacturers achieve and maintain high yields by allowing engineers to collect, correlate, analyze and share critical data. YieldManager combines high-level correlations of disparate data sources with the rapid drill-down of data scope to expedite root cause identification, saving engineering time and focusing resources. It eliminates the need to maintain multiple client-server applications throughout the fab, reducing the cost and complexity of your infrastructure, by providing a single, robust and industry-proven solution.



In modern semiconductor manufacturing the market pressure to rapidly ramp and maintain yields is extreme. Gigabytes of measurement data flood into data collection systems from throughout the fab including metrology, electrical test and defect review. Various systems have been adopted to associate these data sources with yield data in individual efforts to identify the root cause of yield losses. Alone, each source's solution can fail to identify yield loss due to fluctuations from other data sources.

Effective yield analysis manages data from disparate data sources, quickly distinguishing probable root causes from symptoms. A solution must enable correlation of various data types with meaningful statistics and graphical presentation. Fab managers need a robust consolidated data system that also simplifies maintenance yet is scalable to increasing demands. Such proprietary data must be readily available, yet tightly secured. To increase throughput with fast, accurate yield analysis, YieldManager automatically collects critical data from fab- and test-floor sources, then consolidates and standardizes it into a single database. YieldManager provides a powerful analysis tool to rapidly correlate wide ranges of data and drill down to a specific root cause.

YieldManager®

Data Storage Security and Stability

At YieldManager's core is a data system built on the Oracle platform, running in a Unix environment, with field-proven stability. Included is a comprehensive, yet expanding, assortment of loading tools to interpret most data formats. YieldManager has added a new level of security with a server-based utility that gives system administrators more control and flexibility using genuine domain authentication.

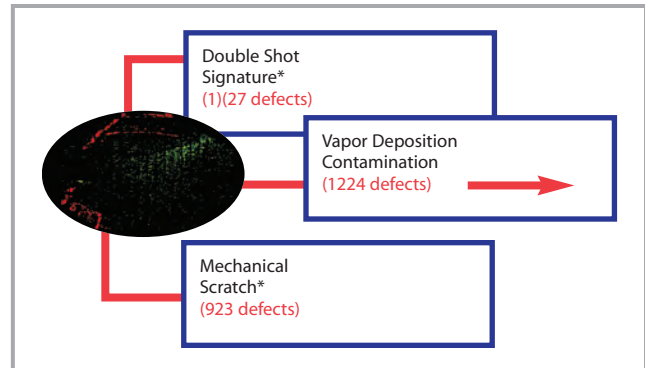
Powerful Interface

The YieldManager Client offers concise data selection in an intuitive graphical interface. Virtually any data condition can be included, excluded, or compared, such as split lots, process tool, die-based zone, or high-low yield. Throughout an analysis session data selection can be further refined with simple point-and-click selection to isolate distinct yield loss sources. A powerful charting engine presents data in an interactive and highly customizable format. Chart types can be rapidly switched through drag-and-drop toolbars that make multiple methods of analysis easily accessible. Common charts with preferences can be saved to further streamline analysis.

YieldManager offers a new 3-tier server model that can ensure uniform data acquisition, analysis and presentation across your team. Datasets, macros and even presentation schemes can be standardized and shared at the server level, keeping teams focused on analysis content rather than format consistency.

Customize and Record Analyses

YieldManager automates the data analysis process by recording VB Script macros that can be modified and extended. Capturing and sharing routine analysis saves time and promotes consistency.



SPAR II - Spatial Pattern Recognition.

Online Help

Online help provides a comprehensive guide for performing root cause analysis in YieldManager. Underlying mathematical assumptions are described in detail, assuring predictable and accurate yield analysis. Video tutorials demonstrate the advanced feature set available to accelerate the learning curve.

More Information

For more information on how YieldManager can enhance yield and throughput for your fab, contact your Magma sales representative or visit our website at www.magma-da.com.

TECHNOLOGY FEATURES:

YieldManager Options

- Additional View Licenses
- Parametric Analysis
- LogicMap
- Adapt
- DIRC
- Smart Sampling
- Spatial Pattern Recognition II

System Requirements

- Server: Sun Solaris 2.8 + or HP-UX 11/ 11i operating system
- Oracle 9.2.0.6
- Application Server: Windows 2003 , Windows Advanced Server
- Client: Windows 2000 / Windows XP operating system

